

[APPARATUS FOR MEASURING OPTO-ELECTRIC PROPERTIES OF OLED AND THE MEASUREMENT METHOD THEREOF]

Abstract

An apparatus for measuring the optoelectric properties of an organic light-emitting device (OLED) comprising a platform, a goniometer, a three-axis moving device and a computer. The goniometer is disposed on one side of the platform and an OLED is disposed on the goniometer. The three-axis moving device is disposed on another side of the platform. The photo-detector is disposed on the three-axis moving device with the photo-detector toward the OLED on the goniometer. The goniometer, the three-axis moving device and the photo-detector are connected to the computer.